

# Parameter Estimation of Continuous Processes Using Financial High-Frequency Data

Vladimír Holý  
University of Economics, Prague  
Faculty of Informatics and Statistics  
Department of Econometrics

Robust  
Rybník  
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# Financial High-Frequency Data

## Financial High-Frequency Data

- **Ultra-high-frequency data** are irregularly spaced time series recorded at highest possible frequency corresponding to each transaction or change in bid/ask prices.
  - *Engle, R. F. (2000). The Econometrics of Ultra-High-Frequency Data. Econometrica, 68(1), 1–22.*
- Financial high-frequency time series include
  - exchange rates,
  - stock prices,
  - commodity prices.
- The **price process** is often modeled with **continuous values** and **continuous time**.
- However, there are some crucial market microstructure specifics such as
  - **rounding error** (prices have discrete values),
  - **discreteness of price changes** (transactions can occur only at discrete times),
  - **bid-ask spread** (transactions can happen either on bid or ask side),
  - **informational effects** (agents do not behave according to the economic theory).

## Market Microstructure Noise

- Market microstructure specifics can be captured by the **model with additive noise**

$$X_i = P_{T_i} + E_i, \quad i = 1, \dots, n,$$

where

- $X_i$  is the **observable price** with discrete time,
  - $P_{T_i}$  is the **efficient price** with continuous time sampled at discrete times  $T_i$ ,
  - $E_i$  is the **market microstructure noise** with discrete time.
- We assume the market microstructure noise to be **independent white noise** and

$$E_i \sim (0, \omega^2).$$

- Generally, the market microstructure noise can be **dependent in time** and **dependent on efficient price**.
  - Hansen, P. R., & Lunde, A. (2006). *Realized Variance and Market Microstructure Noise*. *Journal of Business & Economic Statistics*, 24(2), 127–161.

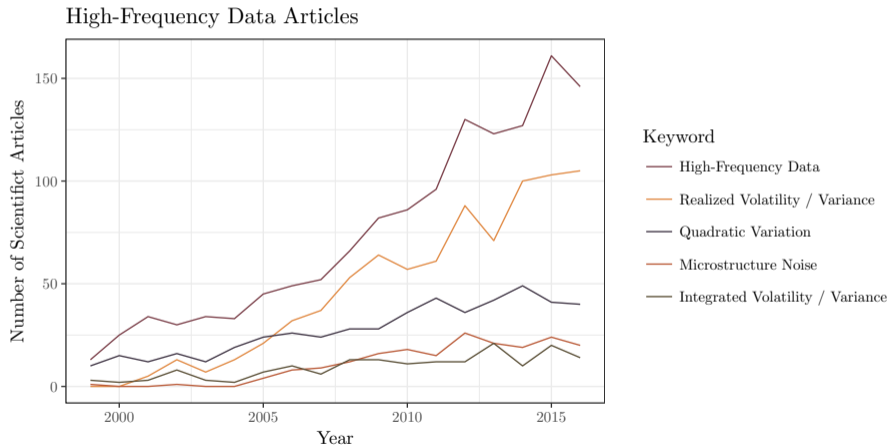
## Non-Parametric Approach

- Estimation of the **quadratic variation** and the **integrated variance**.
  - Zhang, L., Mykland, P. A., & Ait-Sahalia, Y. (2005). *A Tale of Two Time Scales: Determining Integrated Volatility with Noisy High-Frequency Data*. *Journal of the American Statistical Association*, 100(472), 1394–1411.
  - Barndorff-Nielsen, O. E., Hansen, P. R., Lunde, A., & Shephard, N. (2008). *Designing Realized Kernels to Measure the ex post Variation of Equity Prices in the Presence of Noise*. *Econometrica*, 76(6), 1481–1536.
  - Jacod, J., Li, Y., Mykland, P. A., Podolskij, M., & Vetter, M. (2009). *Microstructure Noise in the Continuous Case: The Pre-Averaging Approach*. *Stochastic Processes and Their Applications*, 119(7), 2249–2276.
  - Nolte, I., & Voev, V. (2012). *Least Squares Inference on Integrated Volatility and the Relationship Between Efficient Prices and Noise*. *Journal of Business & Economic Statistics*, 30(1), 94–108.

## Parametric Approach

- Estimation of **Wiener process** parameters.
  - Discrete process contaminated by the independent white noise follow **ARIMA(0,1,1)**.
  - Parameters are estimated by **maximum likelihood of reparametrization**.
  - *Ait-Sahalia, Y., Mykland, P. A., & Zhang, L. (2005). How Often to Sample a Continuous-Time Process in the Presence of Market Microstructure Noise. The Review of Financial Studie, 18(2), 351–416.*
- Estimation of **Ornstein-Uhlenbeck process** parameters.
  - Discrete process contaminated by the independent white noise follow **ARIMA(1,0,1)**.
  - Parameters are estimated by **method of moments, maximum likelihood of reparametrization** and **direct maximum likelihood**.
  - *Holý, V., & Tomanová, P. (2017). Ornstein-Uhlenbeck Process Contaminated by the White Noise: Effects, Estimation and Application. In review.*

# Academic Literature



# Wiener Process



## Wiener Process

- The **standard Wiener process** is a random variable  $W_t$  that satisfies
  - $W_t = 0$ ,
  - for  $0 \leq s < t < u < v$ ,  $W_t - W_s$  and  $W_v - W_u$  are independent,
  - for  $0 \leq s < t$ ,  $W_t - W_s \sim \mathcal{N}(0, t - s)$ .
- We consider the price process given by

$$P_t = \sigma W_t,$$

where  $\sigma > 0$  is the **instantaneous volatility**.

- When the process is **contaminated**, the estimate of  $\sigma$  is **biased**.

## ARIMA(0,1,1) Reparametrization

- We consider **equidistant sampling**  $\Delta = T_i - T_{i-1}$ ,  $i = 1, \dots, n$ .
- The first difference of process  $X_i$  is

$$X_i - X_{i-1} = P_{T_i} - P_{T_{i-1}} + E_i - E_{i-1}.$$

- We can rewrite the process  $X_i$  as

$$X_i = \underbrace{X_{i-1}}_{X_i^{DF}} + \underbrace{R_{T_{i-1}, T_i} + E_i - E_{i-1}}_{X_i^{MA}}, \quad R_{T_{i-1}, T_i} = P_{T_i} - P_{T_{i-1}} \sim N(0, \sigma^2 \Delta).$$

- This is **ARIMA(0,1,1)** process, which can be reparametrized as

$$X_i = \underbrace{X_{i-1}}_{X_i^{DF}} + \underbrace{\theta V_{i-1} + V_i}_{X_i^{MA}}, \quad V_i \sim N(0, \gamma^2).$$

## ARIMA(0,1,1) Estimation

- Parameters  $\theta$  and  $\gamma^2$  can be estimated by maximizing the **likelihood function**

$$L(\theta, \gamma^2) = f_{X_0}(x_0)f_{X_1}(x_1|X_0 = x_0) \cdots f_{X_n}(x_n|X_0 = x_0, \dots, X_{n-1} = x_{n-1}).$$

- To identify  $\sigma^2$  and  $\omega^2$ , we solve the equations

$$\begin{aligned}\gamma^2(1 + \theta^2) &= \text{var}[X_i^{MA}] = \sigma^2\Delta + 2\omega^2, \\ \theta\gamma^2 &= \text{cov}[X_i^{MA}, X_{i-1}^{MA}] = -\omega^2.\end{aligned}$$

- Finally, we get the **original estimates** as

$$\begin{aligned}\hat{\sigma}^2 &= \Delta^{-1}\hat{\gamma}^2(1 + \hat{\theta})^2, \\ \hat{\omega}^2 &= -\hat{\gamma}^2\hat{\theta}.\end{aligned}$$

# Ornstein-Uhlenbeck Process

## Ornstein-Uhlenbeck Process

- The Ornstein-Uhlenbeck process  $P_t$  satisfy

$$dP_t = \tau(\mu - P_t)dt + \sigma dW_t,$$

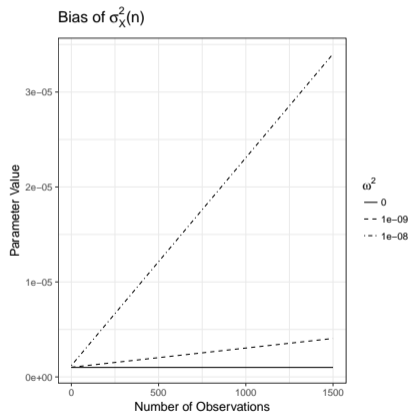
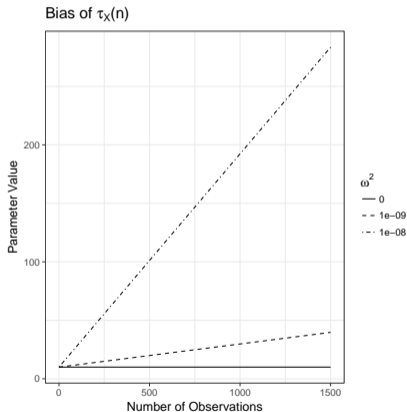
where

- $W_t$  is a Wiener process,
  - $\mu$  is the long term mean level,
  - $\tau > 0$  is the speed of reversion,
  - $\sigma > 0$  is the instantaneous volatility.
- This stochastic differential equation has solution

$$P_t = P_0 e^{-\tau t} + \mu(1 - e^{-\tau t}) + \sigma \int_0^t e^{-\tau(t-s)} dW_s.$$

- When the process is contaminated, the estimates of  $\tau$  and  $\sigma$  are biased.

# Bias of Ornstein-Uhlenbeck Parameters



## ARIMA(1,0,1) Reparametrization

- When considering **equidistant sampling**, the process  $X_i$  can be decomposed as

$$X_i = P_{T_i} + E_i = P_{T_{i-1}} e^{-\tau\Delta} + \mu(1 - e^{-\tau\Delta}) + \sigma \int_0^{\Delta} e^{-\tau(\Delta-s)} dW_s + E_i.$$

- Furthermore, from relation  $P_{T_{i-1}} = X_{i-1} - E_{i-1}$  we obtain

$$X_i = \underbrace{\mu(1 - e^{-\tau\Delta})}_{X_i^{IC}} + \underbrace{e^{-\tau\Delta} X_{i-1}}_{X_i^{AR}} + \underbrace{\sigma \int_0^{\Delta} e^{-\tau(\Delta-s)} dW_s - e^{-\tau\Delta} E_{i-1} + E_i}_{X_i^{MA}}.$$

- This is **ARIMA(1,0,1)** process, which can be reparametrized as

$$X_i = \underbrace{\alpha}_{X_i^{IC}} + \underbrace{\varphi X_{i-1}}_{X_i^{AR}} + \underbrace{\theta V_{i-1} + V_i}_{X_i^{MA}}, \quad V_i \sim N(0, \gamma^2).$$

## ARIMA(1,0,1) Estimation

- Parameters  $\alpha$ ,  $\varphi$ ,  $\theta$  and  $\gamma^2$  can be estimated by maximizing the **likelihood function**

$$L(\alpha, \varphi, \theta, \gamma^2) = f_{X_0}(x_0)f_{X_1}(x_1|X_0 = x_0) \cdots f_{X_n}(x_n|X_0 = x_0, \dots, X_{n-1} = x_{n-1}).$$

- Finally, we get the **original estimates** by solving equations

$$\alpha = X_i^{IC} = \mu(1 - e^{-\tau\Delta}),$$

$$\varphi X_{i-1} = X_i^{AR} = e^{-\tau\Delta} X_{i-1},$$

$$\gamma^2(1 + \theta^2) = \text{var}[X_i^{MA}] = \frac{\sigma^2}{2\tau}(1 - e^{-2\tau\Delta}) + \omega^2(1 + e^{-2\tau\Delta}),$$

$$\theta\gamma^2 = \text{cov}[X_i^{MA}, X_{i-1}^{MA}] = -\omega^2 e^{-\tau\Delta}.$$



## Direct Method of Moments

- We use **four unconditional moments**

$$\begin{aligned}m_1 &= \mathbb{E}[X_i] = \mu, & m_2 &= \text{var}[X_i] = \frac{\sigma^2}{2\tau} + \omega^2, \\m_3 &= \text{cov}[X_i, X_{i-1}] = \frac{\sigma^2}{2\tau} e^{-\tau\Delta}, & m_4 &= \text{cov}[X_i, X_{i-2}] = \frac{\sigma^2}{2\tau} e^{-2\tau\Delta}.\end{aligned}$$

- By replacing **theoretical moments** with their **estimated counterparts**, we get

$$\begin{aligned}\hat{\mu}_{MOM} &= \hat{m}_1, & \hat{\tau}_{MOM} &= \frac{1}{\Delta} \log \frac{\hat{m}_3}{\hat{m}_4}, \\ \hat{\sigma}_{MOM}^2 &= 2 \frac{1}{\Delta} \frac{\hat{m}_3^2}{\hat{m}_4} \log \frac{\hat{m}_3}{\hat{m}_4}, & \hat{\omega}_{MOM}^2 &= \hat{m}_2 - \frac{\hat{m}_3^2}{\hat{m}_4}.\end{aligned}$$

## Direct Maximum Likelihood Estimation

- Observed variables  $X_i$  are **normally distributed** with conditional density functions  $f_{X_{T_i}}(x_{T_i}|X_{T_{i-1}})$  and conditional moments

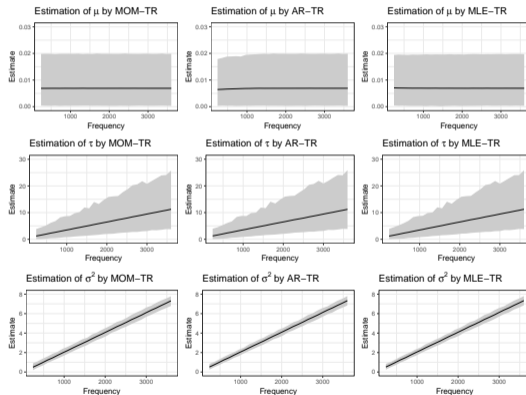
$$E[X_{T_i}|X_{T_{i-1}} = x_{T_{i-1}}] = \frac{x_{T_{i-1}}\sigma^2 + 2\tau\mu\omega^2}{\sigma^2 + 2\tau\omega^2}e^{-\tau\Delta_i} + \mu(1 - e^{-\tau\Delta_i}),$$

$$\text{var}[X_{T_i}|X_{T_{i-1}} = x_{T_{i-1}}] = \frac{\sigma^2\omega^2}{\sigma^2 + 2\tau\omega^2}e^{-2\tau\Delta_i} + \frac{\sigma^2}{2\tau}(1 - e^{-2\tau\Delta_i}).$$

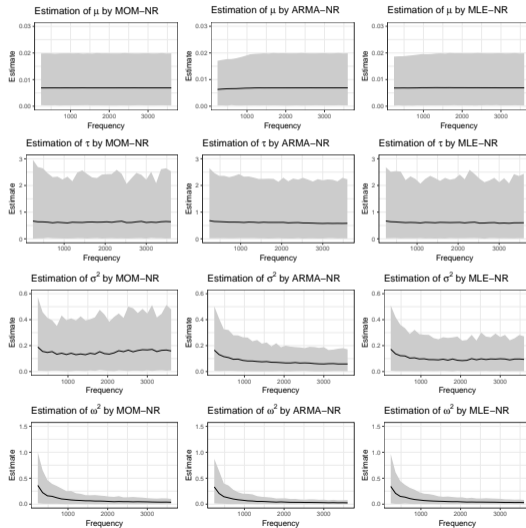
- We get the estimates by maximizing the **logarithmic likelihood function**

$$l(\mu, \tau, \sigma^2, \omega^2) = \sum_{i=1}^n \log f_{X_{T_i}}(x_{T_i}|X_{T_{i-1}} = x_{T_{i-1}}).$$

# Bias of Traditional Parameter Estimates



# Comparison of Proposed Estimators



# Conclusion

## Conclusion

- Ignoring the market microstructure noise leads to significant bias and inconsistency of estimates of the process parameters.
- For the Ornstein-Uhlenbeck process, finite-sample simulations show that the maximum likelihood of ARIMA(1,0,1) reparametrization gives the most accurate estimates.
- We assume the standard Ornstein-Uhlenbeck process and the independent Gaussian white noise. However, both of these assumptions are too restrictive for financial data as many papers suggest. Relaxation of Gaussian assumptions is a topic for the future research.
- High-frequency Ornstein-Uhlenbeck process can be utilized e.g. in pairs trading strategies and stochastic volatility models.

Thank you for your attention!

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